

## From the Editor

### Nashville on My Mind



Nashville, Tennessee, will be the venue for the next Microscopy & Microanalysis meeting, August 7–11, 2011. From the famous Grand Ole Opry to the interesting historical buildings, Nashville has something for everyone.

Light microscopy will be highlighted at this meeting, beginning with an opening plenary presentation by Prof. Stefan Hell, a leader in the movement to break Abbe's wavelength limit. His talk will be about super-resolution microscopy, as will one of the biological symposia.

Thirty symposia will cover the latest developments in light microscopy, scanning probe microscopy, electron microscopy, and microanalysis. Presentations will be given about applications in dozens of fields, among them nanotechnology, cell biology, clinical diagnosis, energy-related materials, and failure analysis. Instrumentation symposia will include topics such as *in-situ* experiments, metallography, tomography, imaging, diffraction, and various types of microanalysis. In addition, there will be two special symposia: A.V. Crewe Memorial Symposium: From Images of Single Atoms to Single Atom Spectroscopy and Beyond; and Microanalysis at 60 Years: A Symposium Dedicated to Raimond Castaing. Of course, if you do not see a symposium that fits your particular area, there will be other sessions on a wide variety of topics. To view descriptions of all symposia, visit the MSA website, [www.microscopy.org](http://www.microscopy.org), and click on "M&M 2011."

Consider submitting an extended abstract for your own presentation in Nashville. Remember that Tuesday, **February 15, 2011, is a hard deadline.**

The Technologists' Forum session this year will be "Correlative Microscopy: High Resolution Fluorescence and Electron Microscopy." There will also be Sunday short courses, "Back to Basics" tutorials, and in-week intensive workshops. In addition, there will be a pre-meeting specialist workshop on "Opportunities, Artifacts, and Interpretation of Aberration-Corrected Electron Microscopy Data."

If you can't find what you need on the website, please contact the program chair, David Giovannucci ([MM2011ProgramChair@microscopy.org](mailto:MM2011ProgramChair@microscopy.org)). David also has an article describing the meeting on page 38.

Charles Lyman  
Editor in Chief

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#### Editorial Staff

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*Editor-in-Chief*  
[charles.lyman@lehigh.edu](mailto:charles.lyman@lehigh.edu)  
(610) 758-4249

**Gennifer Levey**, *Production Manager*  
[gleyev@meridianartproduction.com](mailto:gleyev@meridianartproduction.com)  
(212) 780-0315

**Ron Anderson**, *Executive Editor*  
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**John Shields**, *Humor Editor*  
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M.J. Mrvica Associates, Inc.  
2 West Taunton Avenue, Berlin, NJ 08009  
[mjmrvica@mrvica.com](mailto:mjmrvica@mrvica.com)  
(856) 768-9360

**Amy Reuter**, *Account Manager*  
[areuter@mrvica.com](mailto:areuter@mrvica.com)

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New York, NY 10013-2473  
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